
FOREWORD

Special Section on Recent Development of Electro-Mechanical Devices

Electro-Mechanical Devices (EMD) committee has annually held an International Session on EMD (IS-EMD) to discuss the research results on EMD with not only domestic but foreign researchers since 2001. Moreover, IEICE has annually published special section on the recent development of EMD at the timing to synchronize with the IS-EMD. In this special section, one paper is selected from submitted papers by the Editorial Committee. The paper is interesting for the readers who have basic electrical engineering research issues.

Lastly, I would like to express great appreciation to the Editorial Committee, especially Prof. Yuichi Hayashi and Dr. Kazuaki Miyanaga, Guest Editors, for the remarkable contribution to editorial task of this special section.

Special Section Editorial Committee

Guest Editors: Yuichi Hayashi (Nara Inst. of Sci. & Tech.), Kazuaki Miyanaga (Fujitsu Component)

Guest Associate Editors: Yoshiteru Abe (NTT), Koichiro Sawa (Nippon Inst. of Tech.), Junya Sekikawa (Shizuoka Univ.), Ryo Nagase (Chiba Inst. of Tech.), Makoto Hasegawa (Chitose Inst. of Sci. & Tech.), Masato Mizukami (Muroran Inst. of Tech.)

Yoshiki Kayano (The Univ. of Electro-Communications), Guest Editor-in-Chief

Yoshiki Kayano (*Member*) graduated from Kisarazu National College of Technology, Kisarazu, Japan in 1999. He received B.E., M.E., and Ph.D. in Electrical and Electronic Engineering from Akita University, Japan in 2001, 2003, and 2006, respectively. In 2006, he became a research associate at Akita University. He was a visiting professor at the EMC Laboratory, Missouri University of Science and Technology, Rolla, USA in 2009. He joined the faculty of the University of Electro-Communications in 2016. He is currently an Associate Professor in the Graduate School of Informatics and Engineering, the University of Electro-Communications. His research interest is the electromagnetic interference problem and contact phenomena. He is a member of the IEICE, JIEP and IEEE.

